



CERTIFICATE OF CONFORMANCE
C060 RADIATION TEST

The data supplied with this Test Report that corresponds to the sample test groups referenced below are certified to comply with all requirements of the detail specification and the quality conformance requirements of the general specification. Any exceptions or modifications are stated below.

ADI P/N: AD8561AL/QMLL
Cust. P/N: 5962L00515VHA

General Spec: MIL-PRF-38535
Detail Spec: 5962-00515
Die Type: 62062

REV: J
REV: C

TM1019 Condition D

EXCEPTIONS/MODIFICATIONS:

RADIATION DOSIMETRY:

Radiation Test Log #: ADI-LDR-10-0016

Total Dose Test Date: 2010

Table with 8 columns and 4 rows: Dose Target, Dose Rate, Dose Delivered, TOTAL DOSE. Values include 50k, 75k, 100k, 7.3mRad(si)/s, 50.3k, 24k, 26.7k, 101k.

SAMPLE DATA: Wafer Lot: 635983.1

Table with 8 columns and 10 rows: Wafer #, Travel Log #, Release #, Date Code, Sample S/N's, Biased, UnBiased, Control S/N(s). Values include 6, 15, E145451.1, E145452.1, E143855.1, E143856.1, 0920, 2,3,4, 21,22, 5,6, 23,24,25, 7, 19.

AUTHORIZED SIGNATURES:

Analog Devices, Aerospace Department:

Tom Decker 9/9/11
Name: Date

Signature line Date

Product/Test Engineer

Title

Signature line

Title (Product Assurance Representative)

RADIATION TEST REPORT

PRODUCT:	AD8561AL/QMLL
DIE TYPE:	62062
FILE:	AD8561_LDR.xlsx
DATE CODE:	0920
GAMMA:	0, 50k, 75k, 100k
GAMMA SOURCE:	Co60
DOSE RATE:	7.3mRad/s TM1019.8 Condition D
FACILITIES:	University of Massachusetts @ Lowell
TESTED:	2010

The RADTESTSM DATA SERVICE is a compilation of radiation test results on Analog Devices' Space grade products. It is designed to assist customers in selecting the right product for applications where radiation is a consideration. Many products manufactured by Analog Devices, Inc. have been shown to be radiation tolerant to most tactical radiation environments. Analog Devices, Inc. does not make any claim to maintain or guarantee these levels of radiation tolerance without lot qualification test.

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